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Form 1449 (Modified)

Information Disclosure
Statement By Applicant

(Use Several Sheets if Necessary)

Atty. Docket No. Application No.:

NAI1P066/01.308.01

Applicant:

V. Iyer et al.

Filing Date: Group Art Unit:

01/04/2002

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U.S. Patent Documents

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Examiner		·				Sub-	Filing
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Foreign Patent or Published Foreign Patent Application

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Initial,	No.	No.	Date	Patent Office	Class	class	Yes	No
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Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form 144 (Modified)

Atty: Docket No.

NAII P066

10/039,111

Information Disclosure
Statement By Applicant

TECHNOL
(Use Several Sheets if Necessary)

Atty: Docket No.

Application No.:

10/039,111

V. Iyer et al.

Eiling Date: 2800

01/04/2002

Group Art Unit: Unassigned

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Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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